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United States Patent [19]

Kerschner et al.

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[54] **CAPACITIVE TEST PROBE**

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[73] Assignee: **Hewlett-Packard Company,** Palo Alto, Calif.

[**] Term: **14 Years**

[21] Appl. No.: **1,954**

[22] Filed: **Nov. 25, 1992**

[52] **U.S. Cl.** **D10/80**

[58] **Field of Search** .... 29/401; 73/864.01; 324/72.5, 158 F, 158 P, 537, 678, 690; D10/74, 80; D13/199

[56] **References Cited**

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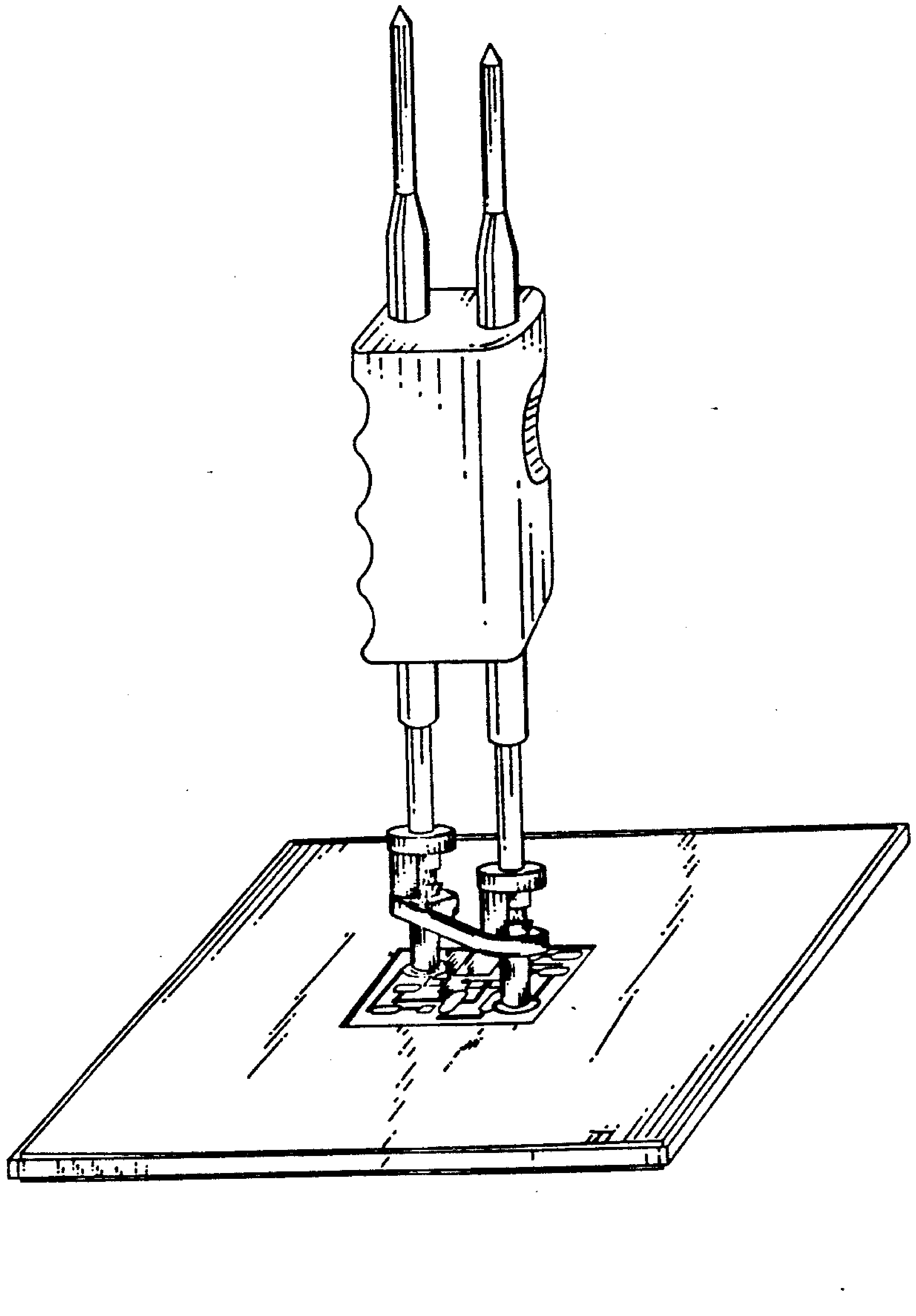
Primary Examiner—Alan P. Douglas
Assistant Examiner—Antoine D. Davis

[57] **CLAIM**

The ornamental design for a capacitive test probe, as shown and described.

DESCRIPTION

FIG. **1** is a top, front perspective view of a capacitive test probe showing our new design;
FIG. **2** is a top plan view thereof;
FIG. **3** is a rear elevation view thereof;
FIG. **4** is a front elevation view thereof;
FIG. **5** is a left side elevation view thereof;
FIG. **6** is a right side elevation view thereof; and,
FIG. **7** is a bottom plan view thereof.



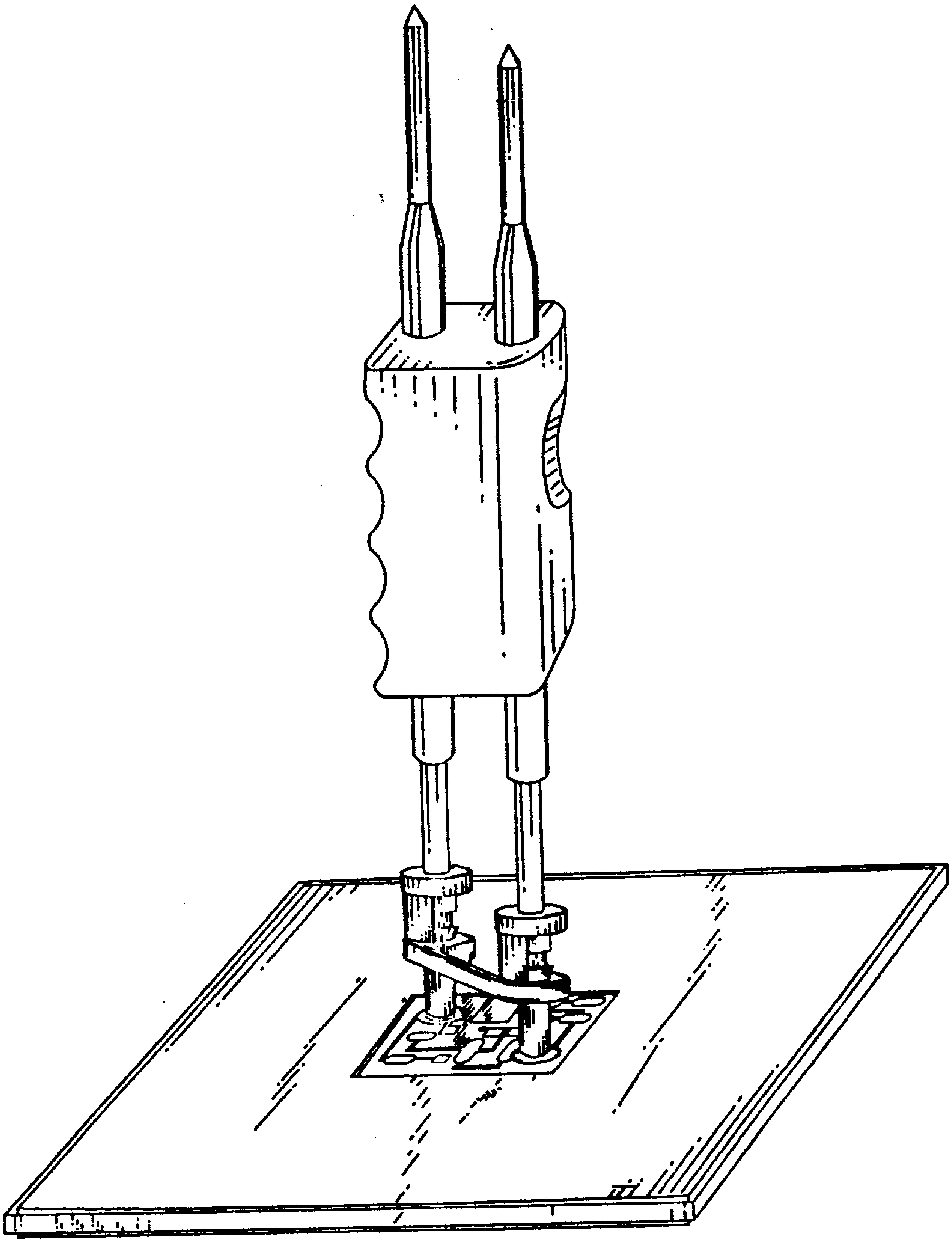
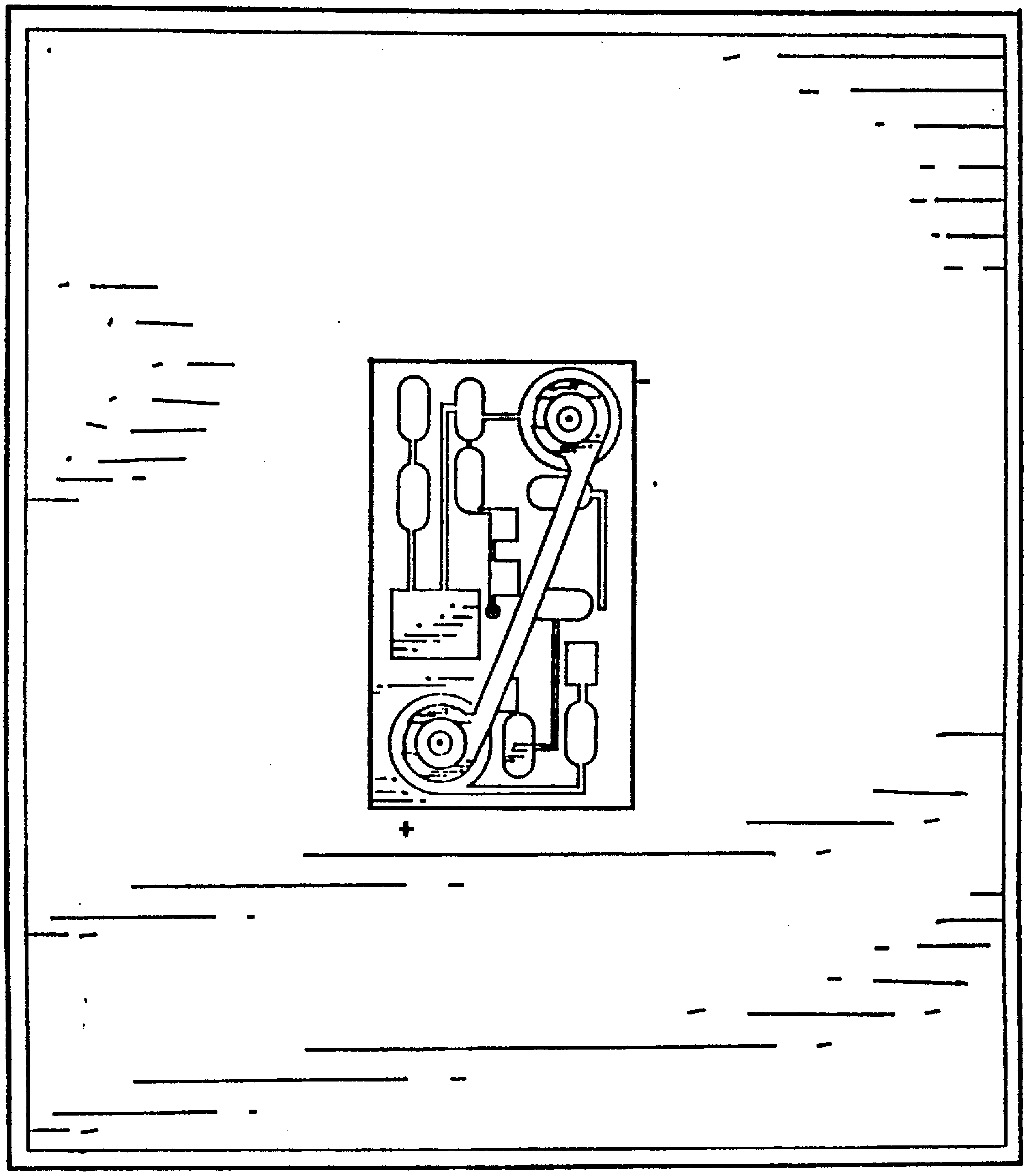


FIG 1

FIG 2



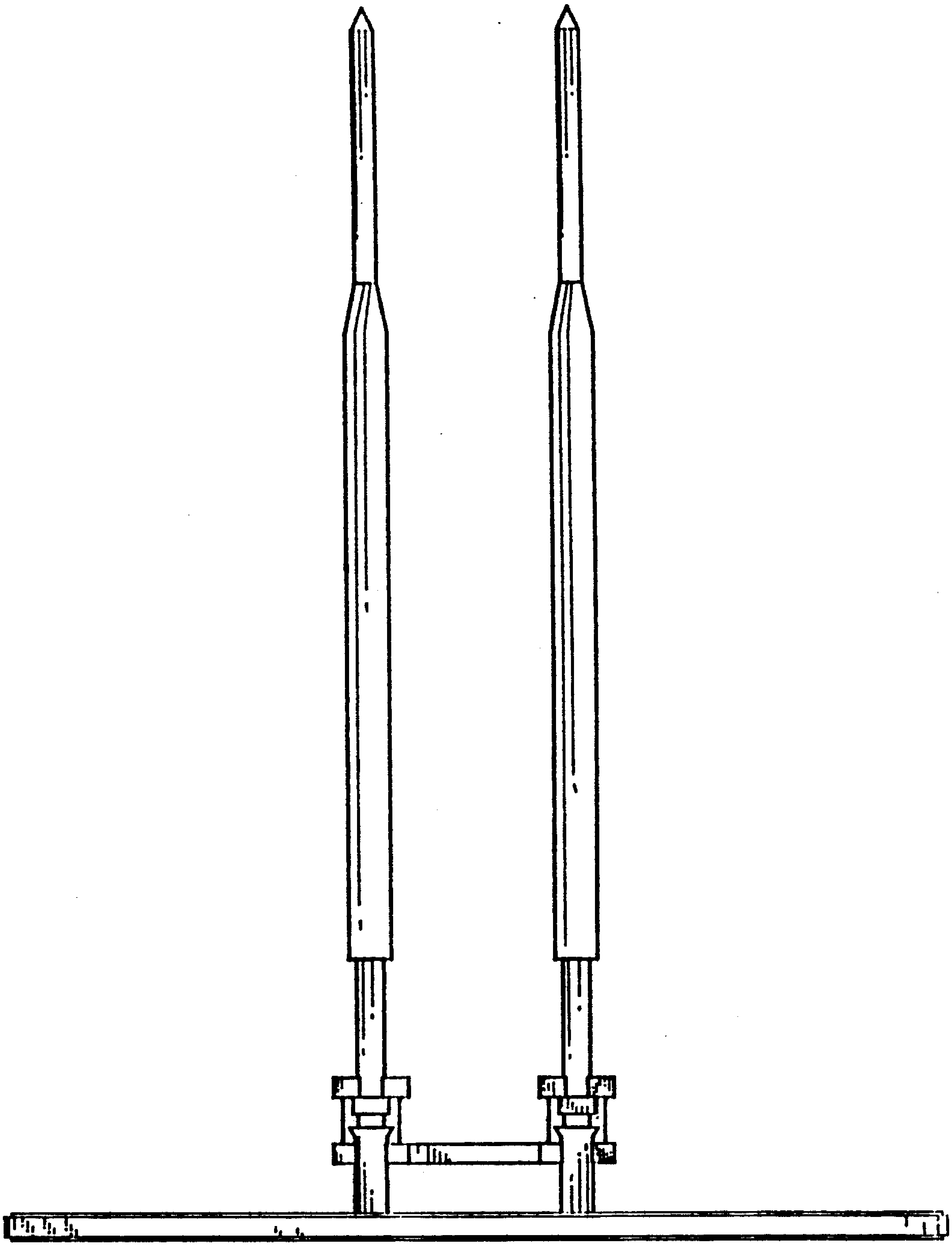


FIG 3

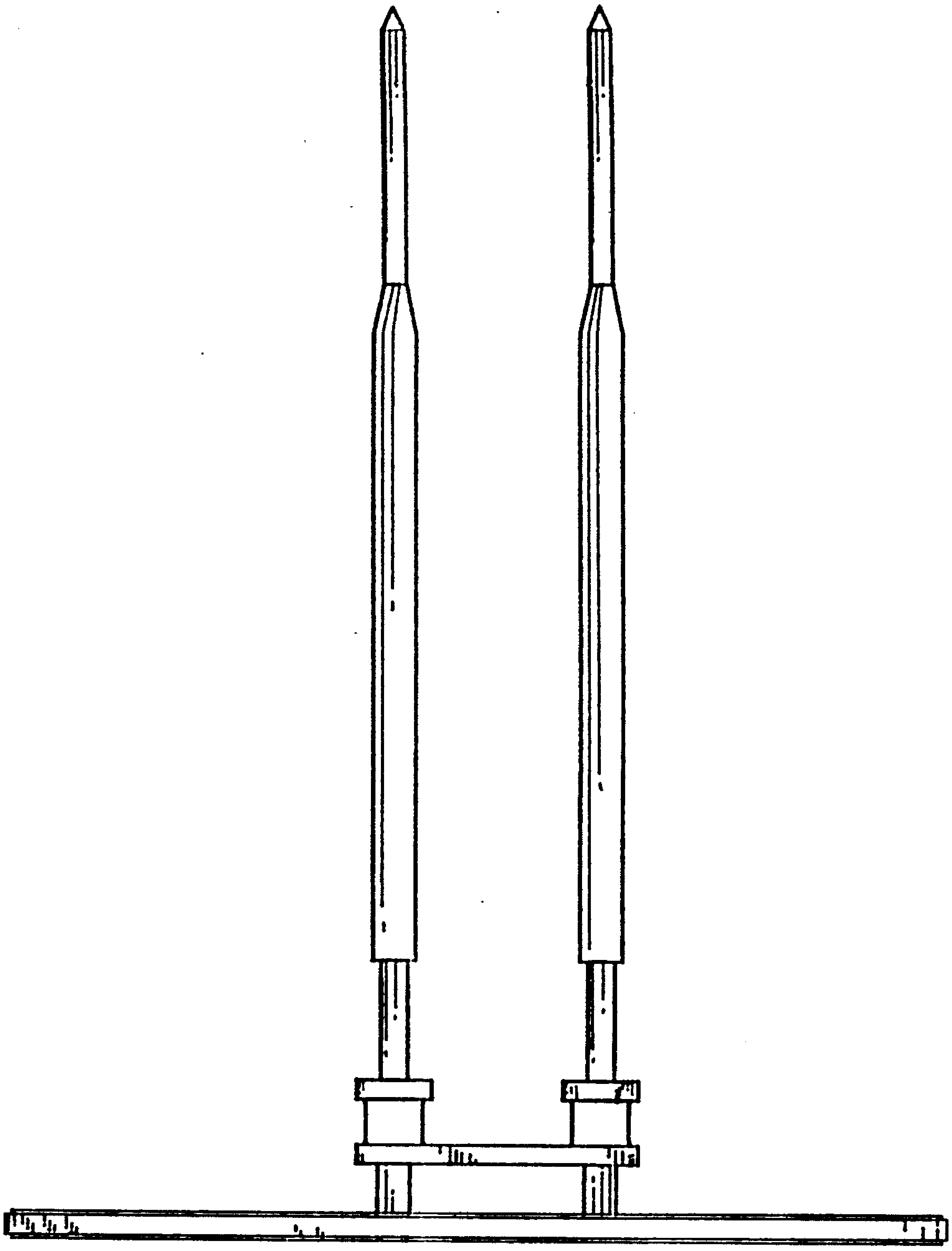


FIG 4

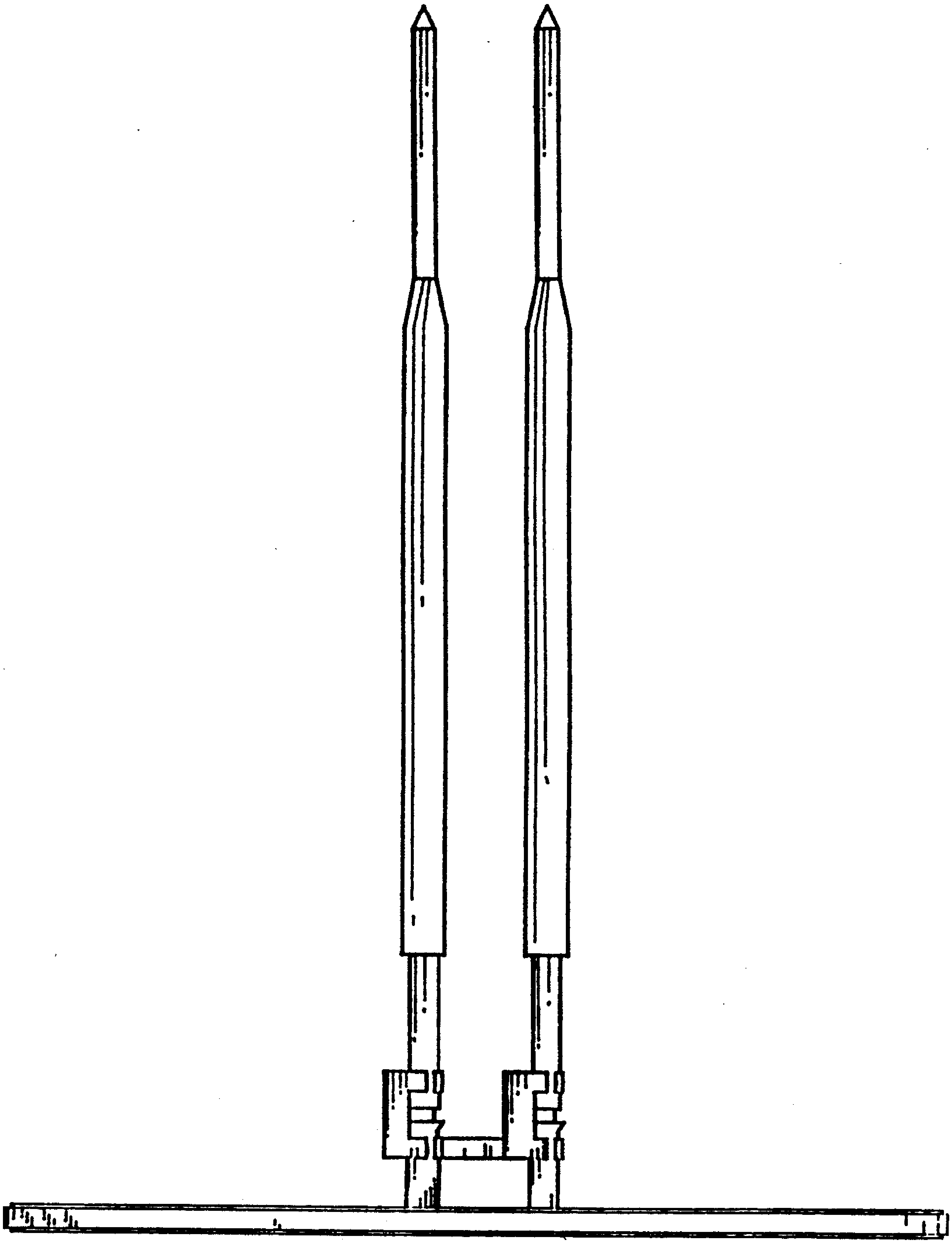


FIG 5

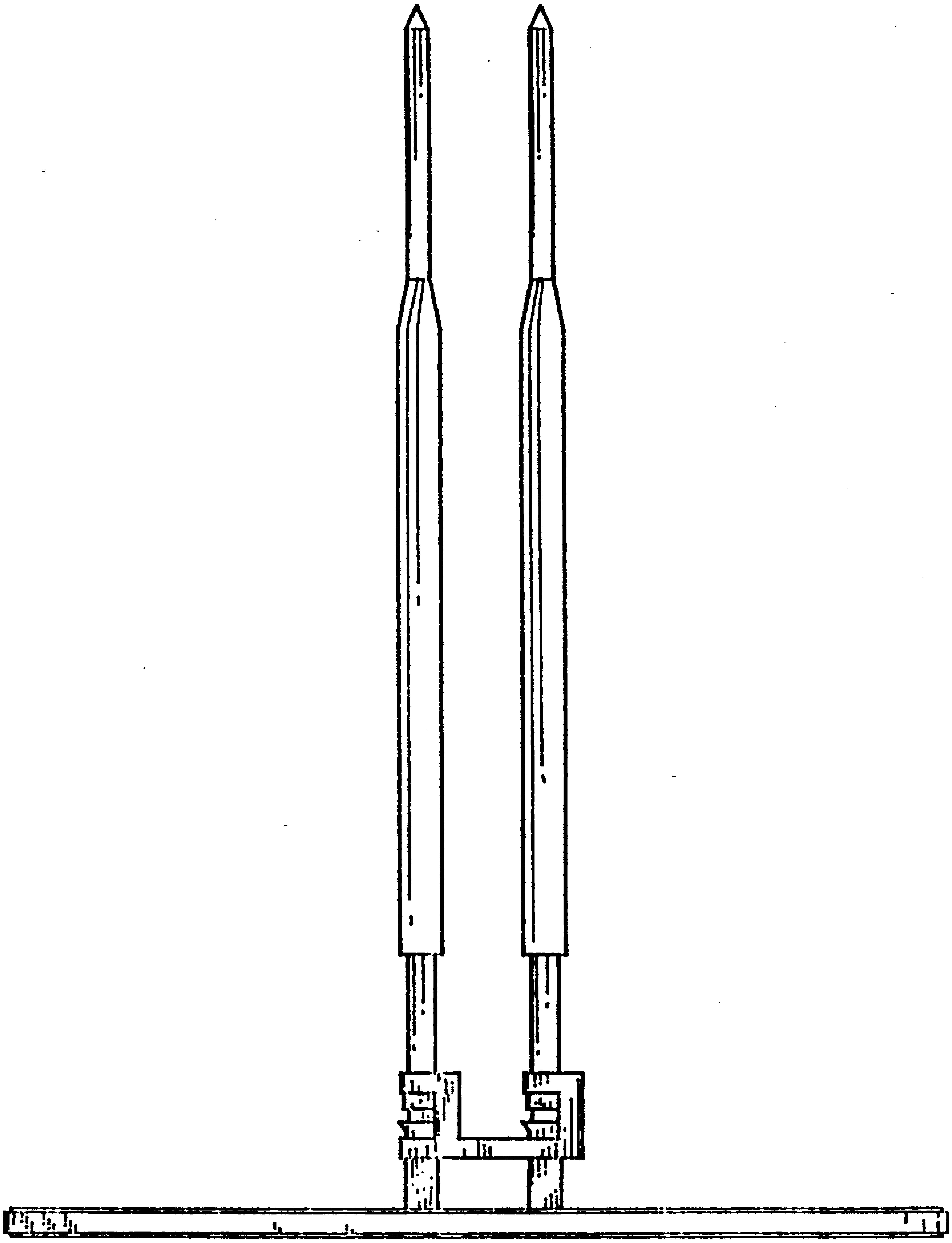


FIG 6

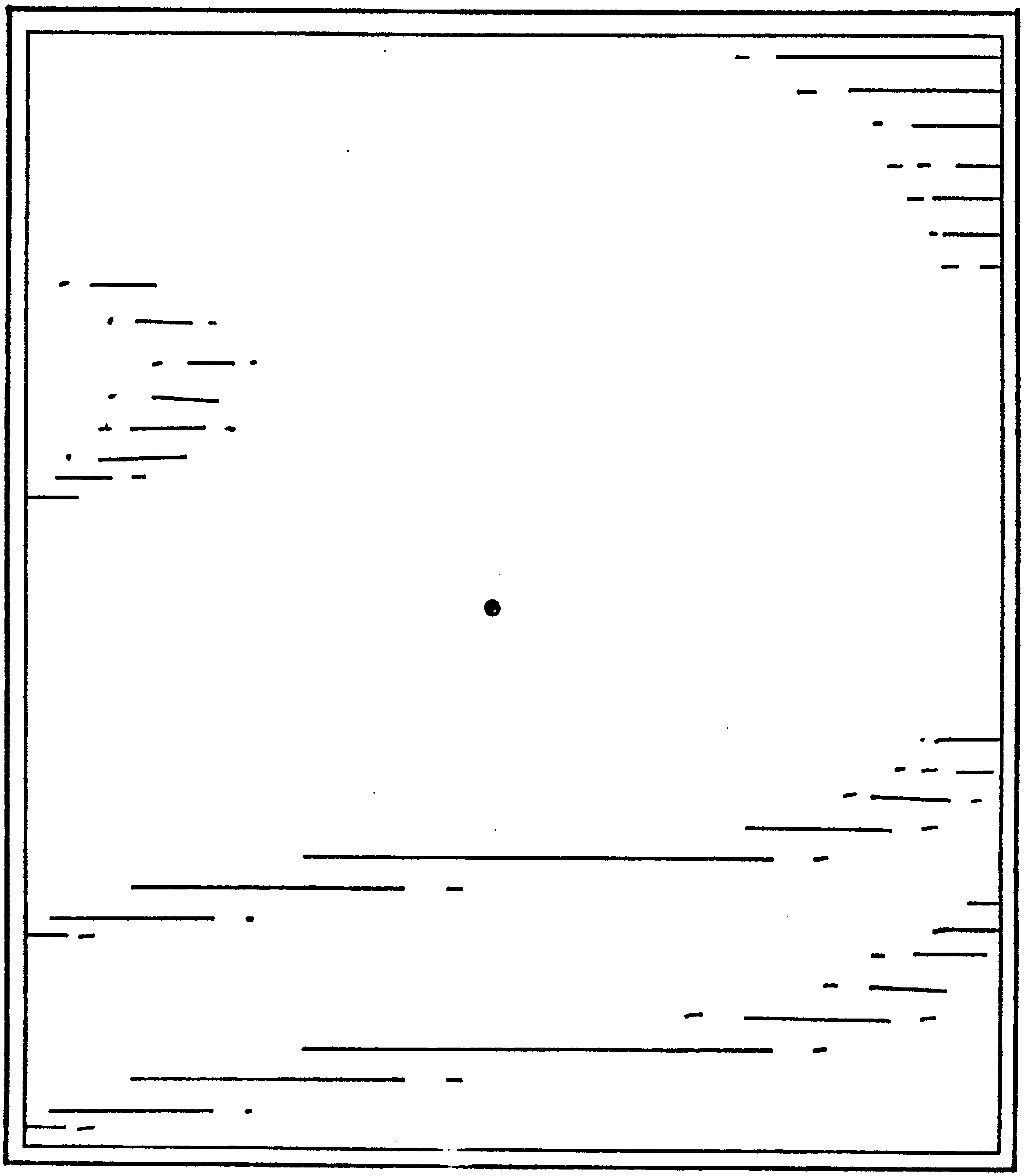


FIG 7